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Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Obsolete
Number of LABs/CLBs	310
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	83
Number of Gates	2500
Voltage - Supply	4.5V ~ 5.5V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 85°C (TA)
Package / Case	100-TQFP
Supplier Device Package	100-VQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/microsemi/a1425a-vqg100i

Ordering Information



Notes:

1. The -2 and -3 speed grades have been discontinued.
2. The Ceramic Pin Grid Array packages PG100, PG133, and PG175 have been discontinued in all device densities, speed grades, and temperature grades.
3. The Plastic Ball Grid Array package BG225 has been discontinued in all device densities (specifically for A1460A), all speed grades, and all temperature grades.
4. Military Grade devices are no longer available for the A1440A device.
5. For more information about discontinued devices, refer to the Product Discontinuation Notices (PDNs) listed below, available on the Microsemi SoC Products Group website:
 PDN March 2001
 PDN 0104
 PDN 0203
 PDN 0604
 PDN 1004

The I/O module output Y is used to bring Pad signals into the array or to feed the output register back into the array. This allows the output register to be used in high-speed state machine applications. Side I/O modules have a dedicated output segment for Y extending into the routing channels above and below (similar to logic modules). Top/Bottom I/O modules have no dedicated output segment. Signals coming into the chip from the top or bottom are routed using F-fuses and LVTs (F-fuses and LVTs are explained in detail in the routing section).

I/O Pad Drivers

All pad drivers are capable of being tristate. Each buffer connects to an associated I/O module with four signals: OE (Output Enable), IE (Input Enable), DataOut, and DataIn. Certain special signals used only during programming and test also connect to the pad drivers: OUTEN (global output enable), INEN (global input enable), and SLEW (individual slew selection). See Figure 2-5.

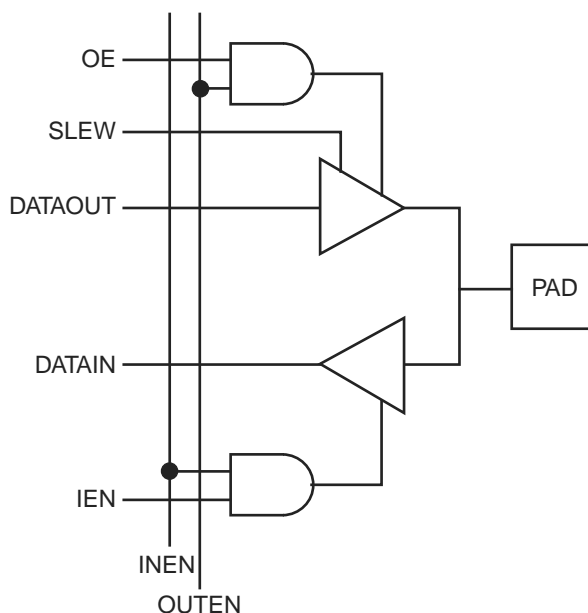


Figure 2-5 • Function Diagram for I/O Pad Driver

Special I/Os

The special I/Os are of two types: temporary and permanent. Temporary special I/Os are used during programming and testing. They function as normal I/Os when the MODE pin is inactive. Permanent special I/Os are user programmed as either normal I/Os or special I/Os. Their function does not change once the device has been programmed. The permanent special I/Os consist of the array clock input buffers (CLKA and CLKB), the hard-wired array clock input buffer (HCLK), the hard-wired I/O clock input buffer (IOCLK), and the hard-wired I/O register preset/clear input buffer (IOPCL). Their function is determined by the I/O macros selected.

Clock Networks

The ACT 3 architecture contains four clock networks: two high-performance dedicated clock networks and two general purpose routed networks. The high-performance networks function up to 200 MHz, while the general purpose routed networks function up to 150 MHz.

Timing Derating

ACT 3 devices are manufactured in a CMOS process. Therefore, device performance varies according to temperature, voltage, and process variations. Minimum timing parameters reflect maximum operating voltage, minimum operating temperature, and best-case processing. Maximum timing parameters reflect minimum operating voltage, maximum operating temperature, and worst-case processing.

Table 2-15 • Timing Derating Factor (Temperature and Voltage)

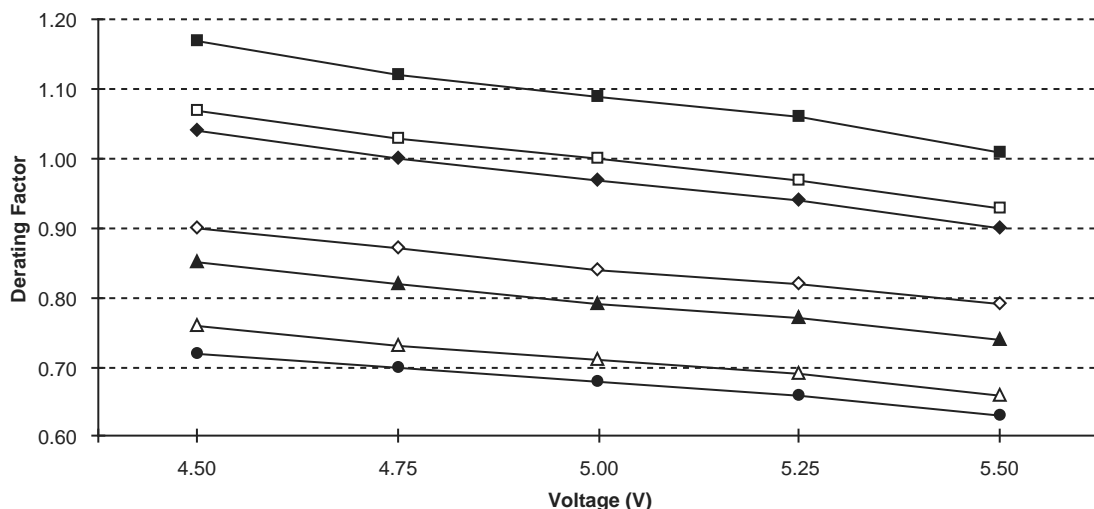
(Commercial Minimum/Maximum Specification) x	Industrial		Military	
	Min.	Max.	Min.	Max.
	0.66	1.07	0.63	1.17

Table 2-16 • Timing Derating Factor for Designs at Typical Temperature ($T_J = 25^\circ\text{C}$) and Voltage (5.0 V)

(Commercial Maximum Specification) x	0.85
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Table 2-17 • Temperature and Voltage Derating Factors (normalized to Worst-Case Commercial, $T_J = 4.75\text{ V}$, 70°C)

	-55	-40	0	25	70	85	125
4.50	0.72	0.76	0.85	0.90	1.04	1.07	1.117
4.75	0.70	0.73	0.82	0.87	1.00	1.03	1.12
5.00	0.68	0.71	0.79	0.84	0.97	1.00	1.09
5.25	0.66	0.69	0.77	0.82	0.94	0.97	1.06
5.50	0.63	0.66	0.74	0.79	0.90	0.93	1.01



Note: This derating factor applies to all routing and propagation delays.

Figure 2-18 • Junction Temperature and Voltage Derating Curves (normalized to Worst-Case Commercial, $T_J = 4.75\text{ V}$, 70°C)

A1440A, A14V40A Timing Characteristics

Table 2-26 • A1440A, A14V40A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C¹

Logic Module Propagation Delays ²		–3 Speed ³		–2 Speed ³		–1 Speed		Std. Speed		3.3 V Speed ¹		Units
Parameter/Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{PD}	Internal Array Module		2.0		2.3		2.6		3.0		3.9	ns
t _{CO}	Sequential Clock to Q		2.0		2.3		2.6		3.0		3.9	ns
t _{CLR}	Asynchronous Clear to Q		2.0		2.3		2.6		3.0		3.9	ns
Predicted Routing Delays⁴												
t _{RD1}	FO = 1 Routing Delay		0.9		1.0		1.1		1.3		1.7	ns
t _{RD2}	FO = 2 Routing Delay		1.2		1.4		1.6		1.8		2.4	ns
t _{RD3}	FO = 3 Routing Delay		1.4		1.6		1.8		2.1		2.8	ns
t _{RD4}	FO = 4 Routing Delay		1.7		1.9		2.2		2.5		3.3	ns
t _{RD8}	FO = 8 Routing Delay		2.8		3.2		3.6		4.2		5.5	ns
Logic Module Sequential Timing												
t _{SUD}	Flip-Flop Data Input Setup	0.5		0.6		0.7		0.8		0.8		ns
t _{HD}	Flip-Flop Data Input Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{SUD}	Latch Data Input Setup	0.5		0.6		0.7		0.8		0.8		ns
t _{HD}	Latch Data Input Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{WASYN}	Asynchronous Pulse Width	1.9		2.4		3.2		3.8		4.8		ns
t _{WCLKA}	Flip-Flop Clock Pulse Width	1.9		2.4		3.2		3.8		4.8		ns
t _A	Flip-Flop Clock Input Period	4.0		5.0		6.8		8.0		10.0		ns
f _{MAX}	Flip-Flop Clock Frequency		250		200		150		125		100	MHz

Notes:

1. VCC = 3.0 V for 3.3 V specifications.
2. For dual-module macros, use t_{PD} + t_{RD1} + t_{PDn} + t_{CO} + t_{RD1} + t_{PDn} or t_{PD1} + t_{RD1} + t_{SUD}, whichever is appropriate.
3. The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at <http://www.microsemi.com/soc/support/notifications/default.aspx#pdn>.
4. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.

A1440A, A14V40A Timing Characteristics (continued)

Table 2-27 • A1440A, A14V40A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C

I/O Module Input Propagation Delays		–3 Speed ¹		–2 Speed ¹		–1 Speed		Std. Speed		3.3 V Speed ¹		Units
Parameter/Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{INY}	Input Data Pad to Y		2.8		3.2		3.6		4.2		5.5	ns
t _{ICKY}	Input Reg IOCLK Pad to Y		4.7		5.3		6.0		7.0		9.2	ns
t _{OCKY}	Output Reg IOCLK Pad to Y		4.7		5.3		6.0		7.0		9.2	ns
t _{ICLRY}	Input Asynchronous Clear to Y		4.7		5.3		6.0		7.0		9.2	ns
t _{OCLRY}	Output Asynchronous Clear to Y		4.7		5.3		6.0		7.0		9.2	ns
Predicted Input Routing Delays²												
t _{RD1}	FO = 1 Routing Delay		0.9		1.0		1.1		1.3		1.7	ns
t _{RD2}	FO = 2 Routing Delay		1.2		1.4		1.6		1.8		2.4	ns
t _{RD3}	FO = 3 Routing Delay		1.4		1.6		1.8		2.1		2.8	ns
t _{RD4}	FO = 4 Routing Delay		1.7		1.9		2.2		2.5		3.3	ns
t _{RD8}	FO = 8 Routing Delay		2.8		3.2		3.6		4.2		5.5	ns
I/O Module Sequential Timing (wrt IOCLK pad)												
t _{INH}	Input F-F Data Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{INSU}	Input F-F Data Setup	1.8		1.7		2.0		2.3		2.3		ns
t _{IDEH}	Input Data Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{IDESU}	Input Data Enable Setup	5.8		6.5		7.5		8.6		8.6		ns
t _{OUTH}	Output F-F Data hold	0.7		0.8		0.9		1.0		1.0		ns
t _{OUTSU}	Output F-F Data Setup	0.7		0.8		0.9		1.0		1.0		ns
t _{ODEH}	Output Data Enable Hold	0.3		0.4		0.4		0.5		0.5		ns
f _{ODESU}	Output Data Enable Setup	1.3		1.5		1.7		2.0		2.0		ns

Notes:

1. The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at <http://www.microsemi.com/soc/support/notifications/default.aspx#pdn>.
2. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.

A1440A, A14V40A Timing Characteristics (continued)

Table 2-28 • A1440A, A14V40A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C

I/O Module – TTL Output Timing ¹		–3 Speed ²		–2 Speed ²		–1 Speed		Std. Speed		3.3 V Speed ¹		Units
Parameter/Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{DHS}	Data to Pad, High Slew		5.0		5.6		6.4		7.5		9.8	ns
t _{DLS}	Data to Pad, Low Slew		8.0		9.0		10.2		12.0		15.6	ns
t _{ENZHS}	Enable to Pad, Z to H/L, High Slew		4.0		4.5		5.1		6.0		7.8	ns
t _{ENZLS}	Enable to Pad, Z to H/L, Low Slew		7.4		8.3		9.4		11.0		14.3	ns
t _{ENHSZ}	Enable to Pad, H/L to Z, High Slew		7.4		8.3		9.4		11.0		14.3	ns
t _{ENLSZ}	Enable to Pad, H/L to Z, Low Slew		7.4		8.3		9.4		11.0		14.3	ns
t _{CKHS}	IOCLK Pad to Pad H/L, High Slew		8.5		8.5		9.5		11.0		14.3	ns
t _{CKLS}	IOCLK Pad to Pad H/L, Low Slew		11.3		11.3		13.5		15.0		19.5	ns
d _{TLHHS}	Delta Low to High, High Slew		0.02		0.02		0.03		0.03		0.04	ns/pF
d _{TLHLS}	Delta Low to High, Low Slew		0.05		0.05		0.06		0.07		0.09	ns/pF
d _{THLHS}	Delta High to Low, High Slew		0.04		0.04		0.04		0.05		0.07	ns/pF
d _{THLLS}	Delta High to Low, Low Slew		0.05		0.05		0.06		0.07		0.09	ns/pF
I/O Module – CMOS Output Timing ¹												
t _{DHS}	Data to Pad, High Slew		6.2		7.0		7.9		9.3		12.1	ns
t _{DLS}	Data to Pad, Low Slew		11.7		13.1		14.9		17.5		22.8	ns
t _{ENZHS}	Enable to Pad, Z to H/L, High Slew		5.2		5.9		6.6		7.8		10.1	ns
t _{ENZLS}	Enable to Pad, Z to H/L, Low Slew		8.9		10.0		11.3		13.3		17.3	ns
t _{ENHSZ}	Enable to Pad, H/L to Z, High Slew		7.4		8.3		9.4		11.0		14.3	ns
t _{ENLSZ}	Enable to Pad, H/L to Z, Low Slew		7.4		8.3		9.4		11.0		14.3	ns
t _{CKHS}	IOCLK Pad to Pad H/L, High Slew		9.0		9.0		10.1		11.8		14.3	ns
t _{CKLS}	IOCLK Pad to Pad H/L, Low Slew		13.0		13.0		15.6		17.3		22.5	ns
d _{TLHHS}	Delta Low to High, High Slew		0.04		0.04		0.05		0.06		0.08	ns/pF
d _{TLHLS}	Delta Low to High, Low Slew		0.07		0.08		0.09		0.11		0.14	ns/pF
d _{THLHS}	Delta High to Low, High Slew		0.03		0.03		0.03		0.04		0.05	ns/pF
d _{THLLS}	Delta High to Low, Low Slew		0.04		0.04		0.04		0.05		0.07	ns/pF

Notes:

1. Delays based on 35 pF loading.
2. The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at <http://www.microsemi.com/soc/support/notifications/default.aspx#pdn>.

A1440A, A14V40A Timing Characteristics (continued)

Table 2-29 • A1440A, A14V40A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C

Dedicated (hardwired) I/O Clock Network		–3 Speed ¹		–2 Speed ¹		–1 Speed		Std. Speed		3.3 V Speed ¹		Units
Parameter/Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{ILOCKH}	Input Low to High (pad to I/O module input)		2.0		2.3		2.6		3.0		3.5	ns
t _{IOPWH}	Minimum Pulse Width High	1.9		2.4		3.3		3.8		4.8		ns
t _{IPOWL}	Minimum Pulse Width Low	1.9		2.4		3.3		3.8		4.8		ns
t _{IOSAPW}	Minimum Asynchronous Pulse Width	1.9		2.4		3.3		3.8		4.8		ns
t _{ILOCKSW}	Maximum Skew		0.4		0.4		0.4		0.4		0.4	ns
t _{IOP}	Minimum Period	4.0		5.0		6.8		8.0		10.0		ns
f _{IOMAX}	Maximum Frequency		250		200		150		125		100	MHz
Dedicated (hardwired) Array Clock												
t _{HCKH}	Input Low to High (pad to S-module input)		3.0		3.4		3.9		4.5		5.5	ns
t _{HCKL}	Input High to Low (pad to S-module input)		3.0		3.4		3.9		4.5		5.5	ns
t _{HPWH}	Minimum Pulse Width High	1.9		2.4		3.3		3.8		4.8		ns
t _{HPWL}	Minimum Pulse Width Low	1.9		2.4		3.3		3.8		4.8		ns
t _{HCKSW}	Delta High to Low, Low Slew		0.3		0.3		0.3		0.3		0.3	ns
t _{HP}	Minimum Period	4.0		5.0		6.8		8.0		10.0		ns
f _{HMAX}	Maximum Frequency		250		200		150		125		100	MHz
Routed Array Clock Networks												
t _{RCKH}	Input Low to High (FO = 64)		3.7		4.1		4.7		5.5		9.0	ns
t _{RCKL}	Input High to Low (FO = 64)		4.0		4.5		5.1		6.0		9.0	ns
t _{RPWH}	Min. Pulse Width High (FO = 64)	3.3		3.8		4.2		4.9		6.5		ns
t _{RPWL}	Min. Pulse Width Low (FO = 64)	3.3		3.8		4.2		4.9		6.5		ns
t _{RCKSW}	Maximum Skew (FO = 128)		0.7		0.8		0.9		1.0		1.0	ns
t _{RP}	Minimum Period (FO = 64)	6.8		8.0		8.7		10.0		13.4		ns
f _{RMAX}	Maximum Frequency (FO = 64)		150		125		115		100		75	MHz
Clock-to-Clock Skews												
t _{IOHCKSW}	I/O Clock to H-Clock Skew	0.0	1.7	0.0	1.8	0.0	2.0	0.0	2.2	0.0	3.0	ns
t _{IORCKSW}	I/O Clock to R-Clock Skew (FO = 64) (FO = 144)	0.0	1.0	0.0	1.0	0.0	1.0	0.0	1.0	0.0	3.0	ns
		0.0	3.0	0.0	3.0	0.0	3.0	0.0	3.0	0.0	3.0	
t _{HRCKSW}	H-Clock to R-Clock Skew (FO = 64) (FO = 144)	0.0	1.0	0.0	1.0	0.0	1.0	0.0	1.0	0.0	1.0	ns
		0.0	3.0	0.0	3.0	0.0	3.0	0.0	3.0	0.0	3.0	

Notes:

1. The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at <http://www.microsemi.com/soc/support/notifications/default.aspx#pdn>.
2. Delays based on 35 pF loading.

A1460A, A14V60A Timing Characteristics

Table 2-30 • A1460A, A14V60A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C¹

Logic Module Propagation Delays ²		–3 Speed ³		–2 Speed ³		–1 Speed		Std. Speed		3.3 V Speed ¹		Units
Parameter/Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{PD}	Internal Array Module		2.0		2.3		2.6		3.0		3.9	ns
t _{CO}	Sequential Clock to Q		2.0		2.3		2.6		3.0		3.9	ns
t _{CLR}	Asynchronous Clear to Q		2.0		2.3		2.6		3.0		3.9	ns
Predicted Routing Delays⁴												
t _{RD1}	FO = 1 Routing Delay		0.9		1.0		1.1		1.3		1.7	ns
t _{RD2}	FO = 2 Routing Delay		1.2		1.4		1.6		1.8		2.4	ns
t _{RD3}	FO = 3 Routing Delay		1.4		1.6		1.8		2.1		2.8	ns
t _{RD4}	FO = 4 Routing Delay		1.7		1.9		2.2		2.5		3.3	ns
t _{RD8}	FO = 8 Routing Delay		2.8		3.2		3.6		4.2		5.5	ns
Logic Module Sequential Timing												
t _{SUD}	Flip-Flop Data Input Setup	0.5		0.6		0.7		0.8		0.8		ns
t _{HD}	Flip-Flop Data Input Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{SUD}	Latch Data Input Setup	0.5		0.6		0.7		0.8		0.8		ns
t _{HD}	Latch Data Input Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{WASYN}	Asynchronous Pulse Width	2.4		3.2		3.8		4.8		6.5		ns
t _{WCLKA}	Flip-Flop Clock Pulse Width	2.4		3.2		3.8		4.8		6.5		ns
t _A	Flip-Flop Clock Input Period	5.0		6.8		8.0		10.0		13.4		ns
f _{MAX}	Flip-Flop Clock Frequency		200		150		125		100		75	MHz

Notes:

1. VCC = 3.0 V for 3.3 V specifications.
2. For dual-module macros, use t_{PD} + t_{RD1} + t_{PDn} + t_{CO} + t_{RD1} + t_{PDn} or t_{PD1} + t_{RD1} + t_{SUD}, whichever is appropriate.
3. The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at <http://www.microsemi.com/soc/support/notifications/default.aspx#pdn>.
4. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.

A1460A, A14V60A Timing Characteristics (continued)

Table 2-31 • A1460A, A14V60A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C

I/O Module Input Propagation Delays		–3 Speed ¹		–2 Speed ¹		–1 Speed		Std. Speed		3.3 V Speed ¹		Units
Parameter/Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{INY}	Input Data Pad to Y		2.8		3.2		3.6		4.2		5.5	ns
t _{ICKY}	Input Reg IOCLK Pad to Y		4.7		5.3		6.0		7.0		9.2	ns
t _{OCKY}	Output Reg IOCLK Pad to Y		4.7		5.3		6.0		7.0		9.2	ns
t _{ICLRY}	Input Asynchronous Clear to Y		4.7		5.3		6.0		7.0		9.2	ns
t _{OCLRY}	Output Asynchronous Clear to Y		4.7		5.3		6.0		7.0		9.2	ns
Predicted Input Routing Delays²												
t _{RD1}	FO = 1 Routing Delay		0.9		1.0		1.1		1.3		1.7	ns
t _{RD2}	FO = 2 Routing Delay		1.2		1.4		1.6		1.8		2.4	ns
t _{RD3}	FO = 3 Routing Delay		1.4		1.6		1.8		2.1		2.8	ns
t _{RD4}	FO = 4 Routing Delay		1.7		1.9		2.2		2.5		3.3	ns
t _{RD8}	FO = 8 Routing Delay		2.8		3.2		3.6		4.2		5.5	ns
I/O Module Sequential Timing (wrt IOCLK pad)												
t _{INH}	Input F-F Data Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{INSU}	Input F-F Data Setup	1.3		1.5		1.8		2.0		2.0		ns
t _{IDEH}	Input Data Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{IDESU}	Input Data Enable Setup	5.8		6.5		7.5		8.6		8.6		ns
t _{OUTH}	Output F-F Data hold	0.7		0.8		0.9		1.0		1.0		ns
t _{OUTSU}	Output F-F Data Setup	0.7		0.8		0.9		1.0		1.0		ns
t _{ODEH}	Output Data Enable Hold	0.3		0.4		0.4		0.5		0.5		ns
f _{ODESU}	Output Data Enable Setup	1.3		1.5		1.7		2.0		2.0		ns

Notes:

5. The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at <http://www.microsemi.com/soc/support/notifications/default.aspx#pdn>.
6. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.

A14100A, A14V100A Timing Characteristics (continued)

Table 2-36 • A14100A, A14V100A Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C

I/O Module – TTL Output Timing ¹		–3 Speed ²		–2 Speed ²		–1 Speed		Std. Speed		3.3 V Speed ¹		Units
Parameter/Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{DHS}	Data to Pad, High Slew		5.0		5.6		6.4		7.5		9.8	ns
t _{DLS}	Data to Pad, Low Slew		8.0		9.0		10.2		12.0		15.6	ns
t _{ENZHS}	Enable to Pad, Z to H/L, High Slew		4.0		4.5		5.1		6.0		7.8	ns
t _{ENZLS}	Enable to Pad, Z to H/L, Low Slew		7.4		8.3		9.4		11.0		14.3	ns
t _{ENHSZ}	Enable to Pad, H/L to Z, High Slew		8.0		9.0		10.2		12.0		15.6	ns
t _{ENLSZ}	Enable to Pad, H/L to Z, Low Slew		7.4		8.3		9.4		11.0		14.3	ns
t _{CKHS}	IOCLK Pad to Pad H/L, High Slew		9.5		9.5		10.5		12.0		15.6	ns
t _{CKLS}	IOCLK Pad to Pad H/L, Low Slew		12.8		12.8		15.3		17.0		22.1	ns
d _{TLHHS}	Delta Low to High, High Slew		0.02		0.02		0.03		0.03		0.04	ns/pF
d _{TLHLS}	Delta Low to High, Low Slew		0.05		0.05		0.06		0.07		0.09	ns/pF
d _{THLHS}	Delta High to Low, High Slew		0.04		0.04		0.04		0.05		0.07	ns/pF
d _{THLLS}	Delta High to Low, Low Slew		0.05		0.05		0.06		0.07		0.09	ns/pF
I/O Module – CMOS Output Timing ¹												
t _{DHS}	Data to Pad, High Slew		6.2		7.0		7.9		9.3		12.1	ns
t _{DLS}	Data to Pad, Low Slew		11.7		13.1		14.9		17.5		22.8	ns
t _{ENZHS}	Enable to Pad, Z to H/L, High Slew		5.2		5.9		6.6		7.8		10.1	ns
t _{ENZLS}	Enable to Pad, Z to H/L, Low Slew		8.9		10.0		11.3		13.3		17.3	ns
t _{ENHSZ}	Enable to Pad, H/L to Z, High Slew		8.0		9.0		10.0		12.0		15.6	ns
t _{ENLSZ}	Enable to Pad, H/L to Z, Low Slew		7.4		8.3		9.4		11.0		14.3	ns
t _{CKHS}	IOCLK Pad to Pad H/L, High Slew		10.4		10.4		12.4		13.8		17.9	ns
t _{CKLS}	IOCLK Pad to Pad H/L, Low Slew		14.5		14.5		17.4		19.3		25.1	ns
d _{TLHHS}	Delta Low to High, High Slew		0.04		0.04		0.05		0.06		0.08	ns/pF
d _{TLHLS}	Delta Low to High, Low Slew		0.07		0.08		0.09		0.11		0.14	ns/pF
d _{THLHS}	Delta High to Low, High Slew		0.03		0.03		0.03		0.04		0.05	ns/pF
d _{THLLS}	Delta High to Low, Low Slew		0.04		0.04		0.04		0.05		0.07	ns/pF

Notes: *

1. Delays based on 35 pF loading.
2. The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at <http://www.microsemi.com/soc/support/notifications/default.aspx#pdn>.

SDO Serial Data Output (Output)

Serial data output for diagnostic probe. SDO is active when the MODE pin is High. This pin functions as an I/O when the MODE pin is Low.

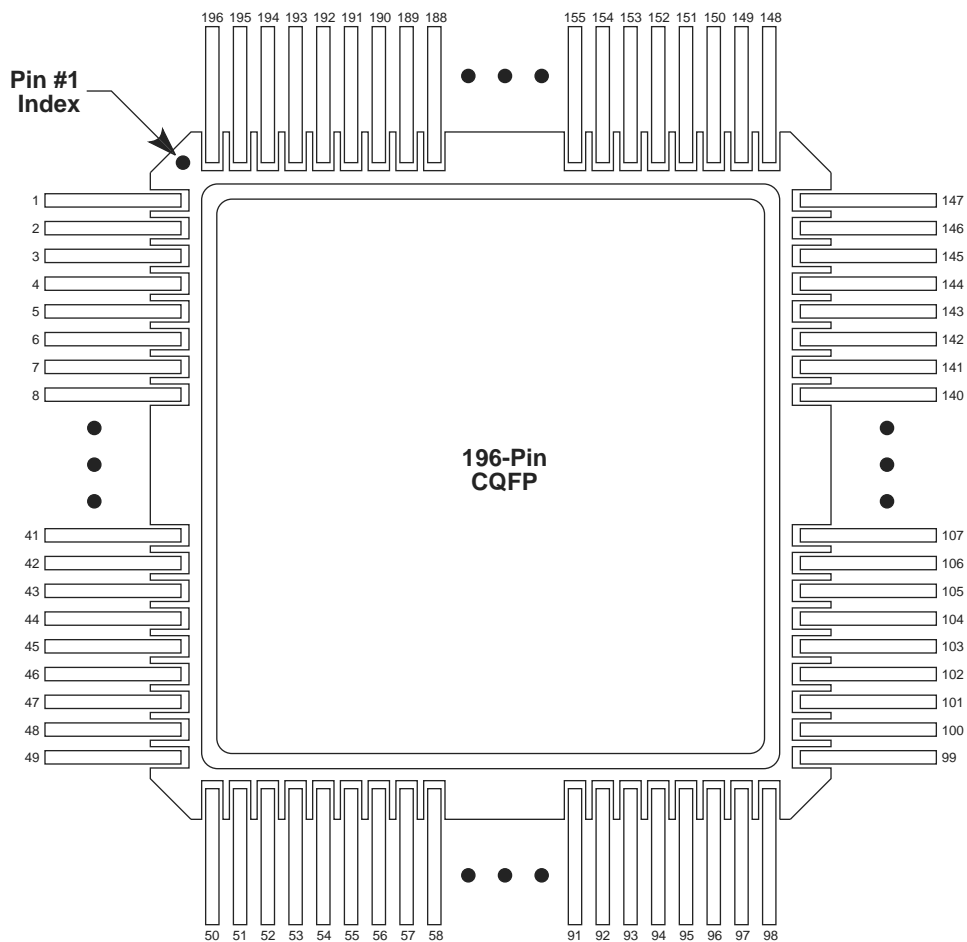
DCLK Diagnostic Clock (Input)

Clock input for diagnostic probe and device programming. DCLK is active when the MODE pin is HIGH. This pin functions as an I/O when the MODE pin is LOW.

VCC 5 V Supply Voltage

HIGH supply voltage.

CQ196

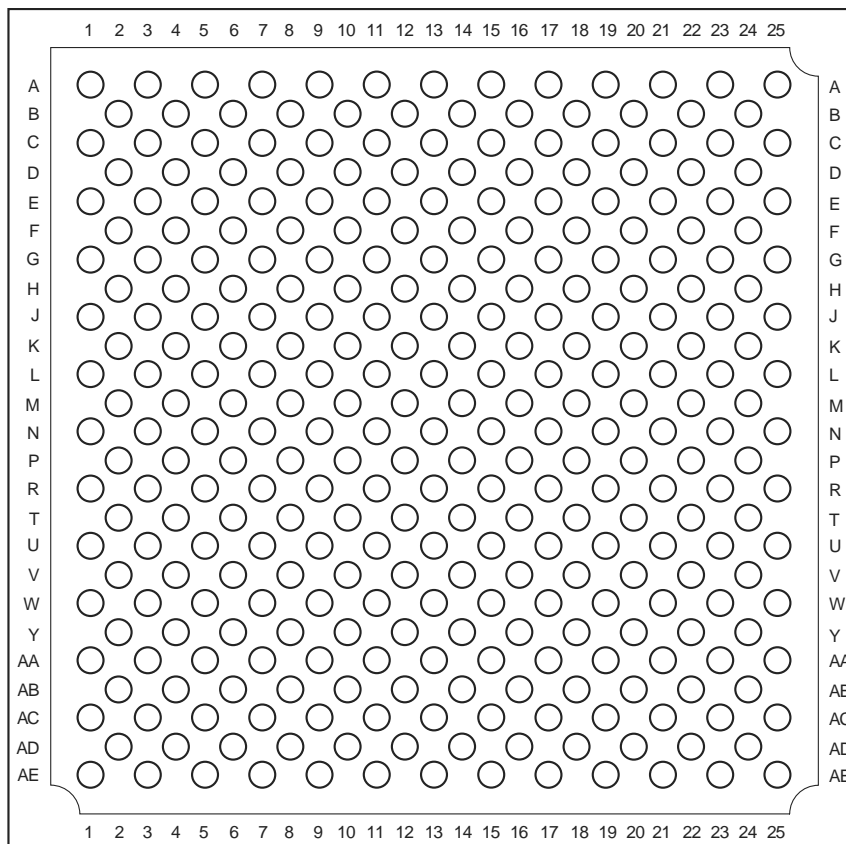


Note: This is the top view.

Note

For Package Manufacturing and Environmental information, visit the Resource Center at <http://www.microsemi.com/soc/products/solutions/package/docs.aspx>

BG313



Note: This is the top view.

Note

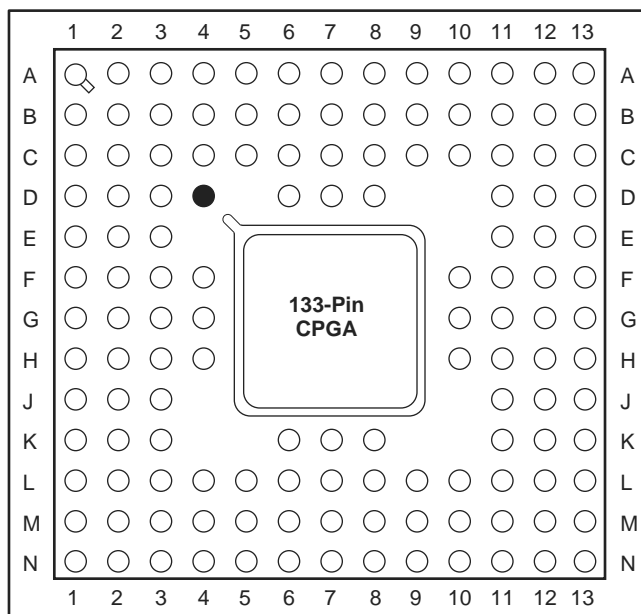
For Package Manufacturing and Environmental information, visit the Resource Center at <http://www.microsemi.com/soc/products/solutions/package/docs.aspx>

PG100	
A1415 Function	Location
CLKA or I/O	C7
CLKB or I/O	D6
DCLK or I/O	C4
GND	C3, C6, C9, E9, F3, F9, J3, J6, J8, J9
HCLK or I/O	H6
IOCLK or I/O	C10
IOPCL or I/O	K9
MODE	C2
PRA or I/O	A6
PRB or I/O	L3
SDI or I/O	B3
SDO	L9
VCC	B6, B10, E11, F2, F10, G2, K2, K6, K10

Notes:

1. All unlisted pin numbers are user I/Os.
2. NC denotes no connection.
3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.
4. The PG100 package has been discontinued.

PG133



Note: This is the top view.

Note

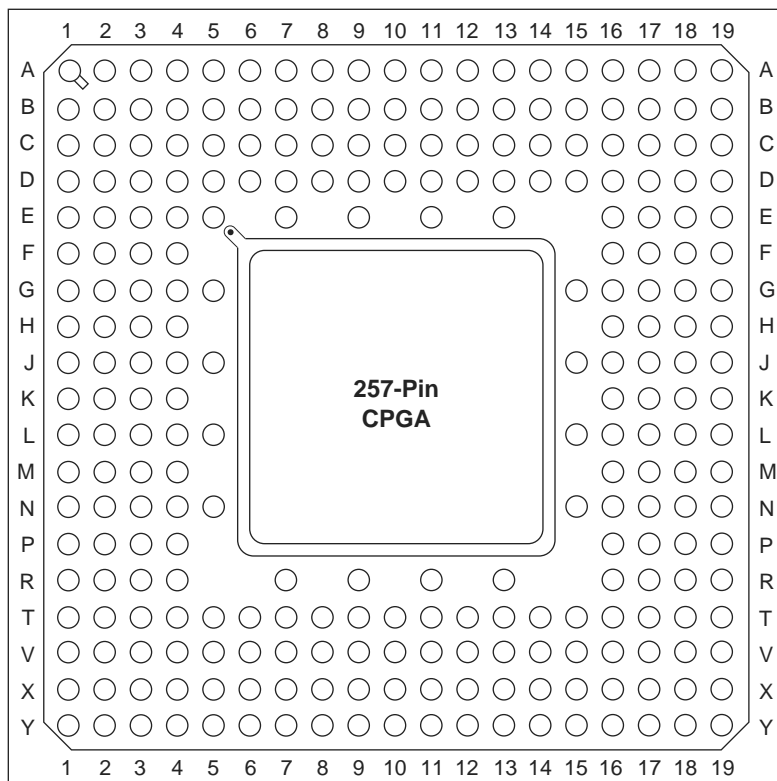
For Package Manufacturing and Environmental information, visit the Resource Center at <http://www.microsemi.com/soc/products/solutions/package/docs.aspx>

PG133	
A1425 Function	Location
CLKA or I/O	D7
CLKB or I/O	B6
DCLK or I/O	D4
GND	A2, C3, C7, C11, C12, F10, G3, G11, L3, L7, L11, M3, N12
HCLK or I/O	K7
IOCLK or I/O	C10
IOPCL or I/O	L10
MODE	E3
NC	A1, A7, A13, G1, G13, N1, N7, N13
PRA or I/O	A6
PRB or I/O	L6
SDI or I/O	C2
SDO	M11
VCC	B2, B7, B12, E11, G2, G12, J2, J12, M2, M7, M12

Notes:

1. All unlisted pin numbers are user I/Os.
2. NC denotes no connection.
3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.
4. The PG133 package has been discontinued.

PG257



Note: This is the top view.

Note

For Package Manufacturing and Environmental information, visit the Resource Center at <http://www.microsemi.com/soc/products/solutions/package/docs.aspx>

Revision	Changes	Page
Revision 2 (continued)	In the "Package Pin Assignments" section, notes were added to the pin tables for the following packages, stating that they are discontinued: "BG225" "PG100" "PG133" "PG175"	3-20 3-24 3-26 3-28
Revision 1 (June 2006)	RoHS compliant information was added to the "Ordering Information" section.	II